



Title of Change:	5-inch Production line closure of ON Semiconductor Niigata Co., Ltd. (OSNC)	
Proposed first ship date:	18 January 2019	
Contact information:	Contact your local ON Semiconductor Sales Office or <Yukio.Kudo@onsemi.com><Katsumi.Yamamoto@onsemi.com>	
Samples:	Contact your local ON Semiconductor Sales Office or <PCN.samples@onsemi.com> Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change.	
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or < Satoru.Fujinuma@onsemi.com>.	
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>	
Change Part Identification:	Date Code	
Change Category:	<input checked="" type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____	
Change Sub-Category(s):	<input type="checkbox"/> Manufacturing Site Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input checked="" type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____	
Sites Affected:	ON Semiconductor Sites: ON Niigata, Japan	External Foundry/Subcon Sites: None
Description and Purpose:		
This final notification announces the elimination of Hydrazine in ON Semiconductor Niigata Co., Ltd. (OSNC) Japan for parts listed in this PCN. The related products are transferred to a process that does not use Hydrazine on the same site OSNC.		
Change Point	Before Change Description	After Change Description
Fab (OSNC)	N1 Fab (Minimum rule=0.8um, Class=10)	N1 Fab (Minimum rule=0.8um, Class=10) AND N2 Fab (Minimum rule=0.25um, Class=1)
Equipment	5inch equipment	6inch equipment (Each function is the same)
Si Sub material	5inch wafer	6inch wafer (No change except wafer diameter)

**Reliability Data Summary:**

QV DEVICE NAME : LV5696P-E

PACKAGE : HZIP15J

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Tj=150°C, 100 % max rated Vcc	1008 hrs	0/77
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/77
TC	JESD22-A104	Ta= -65°C to +150°C	500 cyc	0/77
THB	JESD22-A101	85°C, 85% RH, bias	1008 hrs	0/77
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/77
HBM	JS001	100pF, 1.5kohm, V=+/-2KV	-	0/3
CDM	JS002	V=+/-500V	-	0/3

Note:

Judgment Criteria: Judgment Criteria are due to the limits of the electrical characteristics in the detail specification.

Electrical Characteristic Summary:

There is no change in the electrical performance. Datasheet specifications remain unchanged.

List of Affected Parts:

Part Number	Qualification Vehicle
LV8139JA-AH	LV5696P-E
LV8405V-TLM-E	LV5696P-E

Japanese translation of the notification starts here.
通知の日本語訳はここから始まります。

Note: The Japanese version is for reference only. In case of any differences between the English and Japanese version, the English version shall control.

注：日本語版は参照用です。英語版と日本語版の違いがある場合は、英語版が優先されます。



信頼性データの要約:

QV 素子名: LV5696P-E

パッケージ: HZIP15J

テスト	仕様	条件	間隔	結果
HTOL	JESD22-A108	Tj=150°C, 100 % max rated Vcc	1008 hrs	0/77
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/77
TC	JESD22-A104	Ta= -65°C to +150°C	500 cyc	0/77
THB	JESD22-A101	85°C, 85% RH, bias	1008 hrs	0/77
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/77
HBM	JS001	100pF, 1.5kohm, V=+/-2KV	-	0/3
CDM	JS002	V=+/-500V	-	0/3

注:

判定基準: 判定基準は、詳細仕様での電気的特性の制限によります。

電気的特性の要約:

電気的性能に変更はありません。データシート仕様に変更はありません。

影響を受ける部品の一覧:

部品番号	品質試験用ピークル
LV8139JA-AH	LV5696P-E
LV8405V-TLM-E	LV5696P-E



Appendix A: Changed Products

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Product	Customer Part Number	Qualification Vehicle
LV8139JA-AH		LV5696P-E
LV8405V-TLM-E		LV5696P-E